Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	"5210415".pn.	USPAT	OR	ON	2005/09/07 08:08
L2	78 <del>4</del>	382/128.ccls.	USPAT	OR	ON	2005/09/07 08:08
L3	63	382/128.ccls. and (tissue with bone)	USPAT	OR	ON	2005/09/07 08:09
L4	4	382/128.ccls. and (tissue with bone) and decomposition	USPAT	OR	ON	2005/09/07 08:09
L5	1	382/128.ccls. and (tissue with bone) with parameter	USPAT	OR	ON	2005/09/07 08:10
L6	4	382/128.ccls. and (tissue with bone) same parameter	USPAT	OR	ON	2005/09/07 08:10
L7	10	382/128.ccls. and (tissue with bone) same (parameter or coefficient or weight\$4)	USPAT	OR	ON	2005/09/07 08:13
L8	208	"378".clas. and (tissue with bone) same (parameter or coefficient or weight\$4)	USPAT	OR	ON	2005/09/07 08:14
L9	71	"250".clas. and (tissue with bone) same (parameter or coefficient or weight\$4)	USPAT	OR	ON	2005/09/07 08:17
L10	3	"250".clas. and (tissue with bone) same (parameter or coefficient or weight\$4) and decompos\$5	USPAT	OR	ON	2005/09/07 08:17

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S36	530174	(decompos\$5 or (subtract\$4 near4 image))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/06 09:51
S37	22984	default with parameter	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR .	ON	2005/09/06 09:57
S38 .	11	S36 with S37	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/06 09:51
S40	78213	(default or initial\$7 or loop) with parameter	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/06 09:56
S41	71	S36 with S40	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/06 09:57
S42	95504	bone and tissue	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/06 09:57
S43	8	S41 and S42	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/06 09:57
S44	1010327	parameter	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/06 09:58

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S45	2183	S36 with S44	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/06 09:58
S46	2393808	parameter or setting	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/06 09:58
S47	4016	S36 with S46	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/06 09:59
S48	117	S47 and S42	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/06 09:59
S49	43	(US-20040081280-\$ or US-20030169848-\$ or US-20030152258-\$ or US-20030147497-\$ or US-20030142787-\$).did. or (US-6917697-\$ or US-6842638-\$ or US-6836557-\$ or US-6816572-\$ or US-6792072-\$ or US-6754398-\$ or US-6661873-\$ or US-6625303-\$ or US-6624439-\$ or US-6624439-\$ or US-6574302-\$ or US-6549803-\$ or US-6421419-\$ or US-6351660-\$ or US-6343111-\$ or US-6169817-\$ or US-5862249-\$ or US-5852647-\$ or US-5841890-\$ or US-5796860-\$).did. or (US-5717791-\$ or US-5633509-\$ or US-5400377-\$ or US-54044-\$ or US-5400377-\$ or US-5210415-\$ or US-5049748-\$ or US-4813061-\$ or US-20030152258-\$ or US-6343111-\$ or US-6343111-\$ or US-6343111-\$ or US-6343111-\$ or US-6343111-\$ or US-540377-\$ or US-6343111-\$ or US-4813061-\$ or US-4217641-\$).did. or (US-20030152258-\$ or US-6343111-\$ or JP-03133278-\$). did.	US-PGPUB; USPAT; DERWENT	OR	OFF	2005/09/06 10:45
S50	29	S49 and filter\$4	USPAT	OR	OFF	2005/09/06 10:45
S51	22	S49 and filter\$4 not avinash	USPAT	OR	OFF	2005/09/06 10:45

S52	24	S49 and filter\$4 not avinash.in.	USPAT	OR	OFF	2005/09/06 10:47
S53	16	S52 and decompos\$5	USPAT	OR	ON	2005/09/06 10:48
S54	14	S52 and decompos\$5 and	USPAT	OR	ON	2005/09/06 10:48
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IEE CNF	IEE Conference Proceeding		[Engineering in Medicine and Biology, 2002. 24th Annual Conference and the Meeting of the Biomedical Engineering Society] EMBS/BMES Conference, 20 the Second Joint	
IEEE STD	IEEE Standard		Volume 3, 23-26 Oct. 2002 Page(s):2523 - 2524 vol.3	
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			<ol> <li>Characterization of bony tissues from ultrasonic backscattering using s Shyh-Hau Wang; Fu-Chuan Tsai; Yu-Li Hung; Ultrasonics Symposium, 2001 IEEE Volume 2, 7-10 Oct. 2001 Page(s):1205 - 1208 vol.2 Digital Object Identifier 10.1109/ULTSYM.2001.991935</li> </ol>	ite
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